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1 A low-power 256-Mb SDRAM with an on-chip thermometer and bias reference line sensing scheme

Jung Pill Kim; Woodward Yang; Han-Yuan Tan;

Solid-State Circuits, IEEE Journal of Volume: 38, Issue: 2, Feb. 2003

Pages: 329 - 337

[Abstract] [PDF Full-Text (768 KB)] **IEEE JNL** 

2 Bulk damage caused by single protons in SDRAMs

Shindou, H.; Kuboyama, S.; Ikeda, N.; Hirao, T.; Matsuda, S.;

Nuclear Science, IEEE Transactions on , Volume: 50 , Issue: 6 , Dec. 2003

Pages: 1839 - 1845

[Abstract] [PDF Full-Text (303 KB)] **IEEE JNL** 

3 Performance improvements in high-density DRAM application using µm body-contacted SOI technology

Jong-Wook Lee; Hyung-Ki Kim; Jóńg-Soo Kim; Won-Chang Lee; Jeong-Hee C Dae-Gwan Kang; Yo-Hwan Koḥ;

SOI Conference, 2000 IEEE International, 2=5 Oct. 2000-

Pages:76 - 77

[Abstract] [PDF Full-Text (128 KB)] **IEEE CNF** 

4 A 1.0 V 256 Mb SDRAM with offset-compensated direct sensing and charge-recycled precharge schemes/

Sim, J.Y.; Kwon, K.W.; Choi, J.H.; Lee,/S.H.; Kim, D.M.; Hwang, H.R.; Chun, Seo, Y.H.; Hwang, H.S.; Seo, D.I.; Ķim, C.; Cho, S.I.; Solid-State Circuits Conference, 2003: Digest of Technical Papers. ISSCC. 200 IEEE International , 2003 ₪

Pages:310 - 495 vol.1

[Abstract] [PDF Full-Text (689 KB)] IEEE CNF

5 DRAM performance improvement by lowering interconnect capacita Weimin Li; Sandhu, G.S.; Chih-Chen Cho; Blalock, G.D.;

Interconnect Technology Conference, 2001. Proceedings of the IEEE 2001

International , 4-6 June 2001

Pages: 78 - 80

[Abstract] [PDF Full-Text (160 KB)] IEEE CNF

# 6 OwL: An interface description language for IP reuse

Suzuki, K.; Ara, K.; Yano, K.;

Custom Integrated Circuits, 1999. Proceedings of the IEEE 1999 , 16-19 May Pages: 406

[Abstract] [PDF Full-Text (372 KB)] IEEE CNF

### 7 FTC piles onto standardization Rambus' skullduggery

Stern, W.;

Micro, IEEE, Volume: 22, Issue: 4, July-Aug. 2002

Pages:6 - 7, 86-7

[Abstract] [PDF Full-Text (459 KB)] IEEE JNL

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